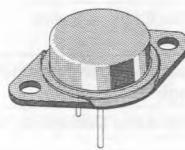


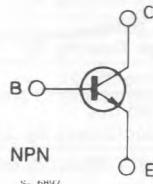
HIGH CURRENT, HIGH SPEED, HIGH POWER TRANSISTOR

DESCRIPTION

The BUX20 is a silicon multiepitaxial planar NPN transistor in modified Jedec TO-3 metal case, intended for use in switching and linear applications in military and industrial equipment.


TO-3

INTERNAL SCHEMATIC DIAGRAM



ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
V_{CBO}	Collector-base Voltage ($I_E = 0$)	160	V
V_{CEX}	Collector-emitter Voltage ($V_{BE} = -1.5$ V)	160	V
V_{CEO}	Collector-emitter Voltage ($I_B = 0$)	125	V
V_{EBO}	Emitter-base Voltage ($I_C = 0$)	7	V
I_C	Collector Current	50	A
I_{CM}	Collector Peak Current ($t_p = 10$ ms)	60	A
I_B	Base Current	10	A
P_{tot}	Total Power Dissipation at $T_{case} \leq 25$ °C	350	W
T_{stg}	Storage Temperature	-65 to 200	°C
T_j	Junction Temperature	200	°C

THERMAL DATA

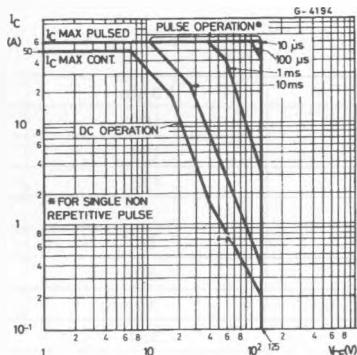
$R_{th\ j-case}$	Thermal Resistance Junction-case	Max	0.5	$^{\circ}\text{C/W}$
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ELECTRICAL CHARACTERISTICS ($T_{case} = 25^{\circ}\text{C}$ unless otherwise specified)

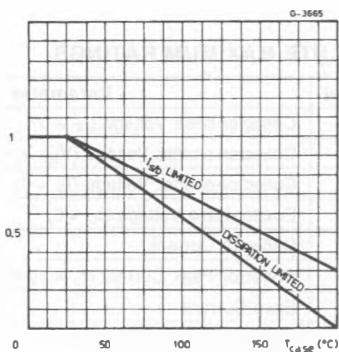
Symbol	Parameter	Test Conditions		Min.	Typ.	Max.	Unit
I_{CEO}	Collector Cutoff Current ($I_B = 0$)	$V_{CE} = 100\text{ V}$				3	mA
I_{CEX}	Collector Cutoff Current	$V_{CE} = 160\text{ V}$	$V_{BE} = -1.5\text{ V}$			3	mA
		$T_{case} = 125^{\circ}\text{C}$	$V_{BE} = -1.5\text{ V}$			12	mA
		$V_{CE} = 160\text{ V}$					
I_{EBO}	Emitter Cutoff Current ($I_C = 0$)	$V_{EB} = 5\text{ V}$				1	mA
$V_{CEO(sus)}$ *	Collector-emitter Sustaining Voltage	$I_C = 200\text{ mA}$		125			V
V_{EBO}	Emitter-base Voltage ($I_C = 0$)	$I_E = 50\text{ mA}$		7			V
$V_{CE(sat)}$ *	Collector-emitter Saturation Voltage	$I_C = 25\text{ A}$	$I_B = 2.5\text{ A}$		0.3	0.6	V
$V_{BE(sat)}$ *	Base-emitter Saturation Voltage	$I_C = 50\text{ A}$	$I_B = 5\text{ A}$		0.55	1.2	V
h_{FE} *	DC Current Gain	$I_C = 25\text{ A}$	$V_{CE} = 2\text{ V}$	20		60	
		$I_C = 50\text{ A}$	$V_{CE} = 4\text{ V}$	10			
$I_{s/b}$	Second Breakdown Collector Current	$V_{CE} = 40\text{ V}$	$t = 1\text{ s}$	1.5			A
		$V_{CE} = 20\text{ V}$	$t = 1\text{ s}$	17.5			A
f_T	Transition Frequency	$V_{CE} = 15\text{ V}$	$I_C = 2\text{ A}$	8			MHz
		$f = 10\text{ MHz}$					
t_{on}	Turn-on Time (fig. 2)	$I_C = 50\text{ A}$	$I_{B1} = 5\text{ A}$		0.4	1.5	μs
		$V_{CC} = 60\text{ V}$					
t_s	Storage Time (fig. 2)	$I_C = 50\text{ A}$	$I_{B1} = 5\text{ A}$		0.85	1.2	μs
t_f	Fall Time (fig. 2)	$I_{B2} = -5\text{ A}$	$V_{CC} = 60\text{ V}$		0.1	0.3	μs
	Clamped Es/b Collector Current (fig. 1)	$V_{clamp} = 125\text{ V}$	$L = 500\text{ }\mu\text{H}$	50			A

* Pulsed : pulse duration = 300 μs , duty cycle $\leq 2\%$.

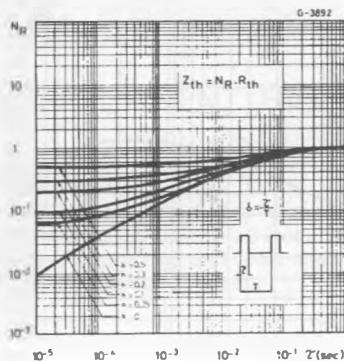
Safe Operating Areas.



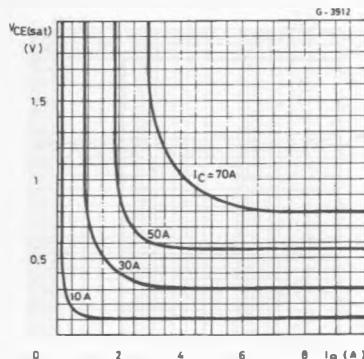
Derating Curves.



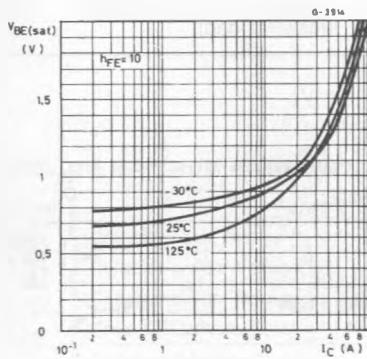
Thermal Transient Response.



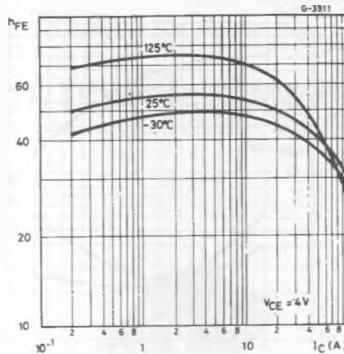
Collector-emitter Saturation Voltage.



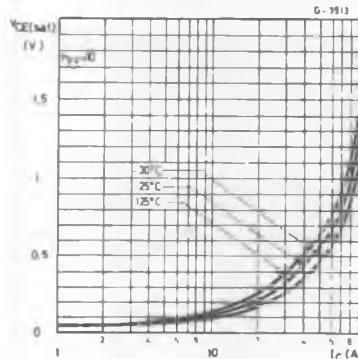
Base-emitter Saturation Voltage.



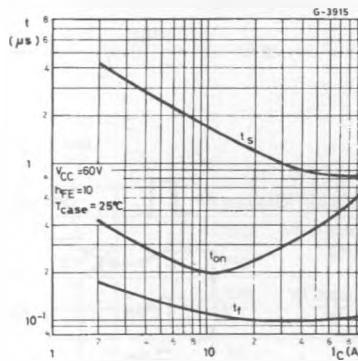
DC Current Gain.



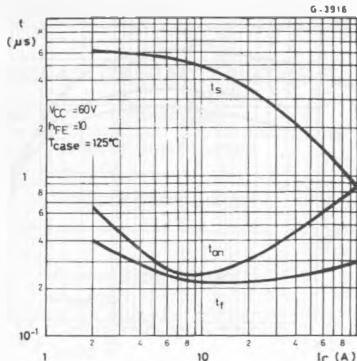
Collector-emitter Saturation Voltage.



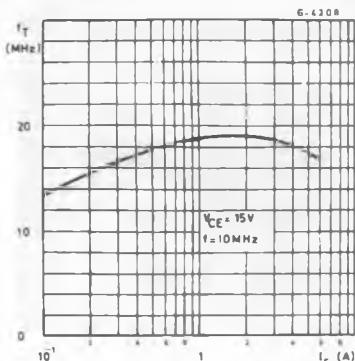
Saturated Switching Characteristics.



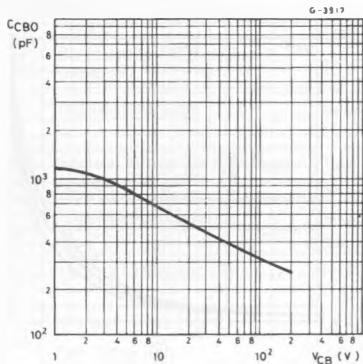
Saturated Switching Characteristics.



Transition Frequency.



Collector-base Capacitance.

Figure 1 : Clamped E_{S/b} Test Circuit.

Clamped Reverse Bias Safe Operating Area.

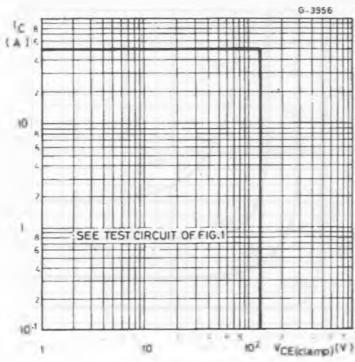


Figure 2 : Switching Times Test Circuit (resistive load).

